



Quality Control Instrument

## X-Rite Ci™ 4200 / Ci™ 4200UV

Benchtop Spectrophotometer

A reliable and accurate benchtop spectrophotometer that serves as the foundation for operations seeking to establish a color control program or one looking to improve an existing program that currently relies on non-spectral devices or visual inspection pass/fail methods.

The Ci4200/Ci4200UV sets the new standard for performance and features in an easy to use compact sphere benchtop solution that when combined with a tiered offering of Color QC and Formulation software applications can be scaled to support a growing color program.



## X-Rite Ci4200 Specifications

<b>Measuring Geometrics</b>	d/8°, DRS spectral engine, Simultaneous SPIN / SPEX
<b>Optical Aperture</b>	8mm measurement area 14mm target window
<b>Light Source</b>	Gas-filled tungsten lamp UVLEDs (Ci4200UV)
<b>Receiver</b>	Blue-enhanced silicon photodiodes
<b>Spectral Range</b>	400 – 700nm
<b>Spectral Interval</b>	10nm – measured 10nm – output
<b>Measurement Range</b>	0 to 200% reflectance
<b>Inter-Instrument Agreement</b>	CIE L*a*b*: Avg. 0.20 $\Delta E^*ab$ based on avg. of 12 BCRA Series II tiles (specular component included) Max. 0.40 $\Delta E^*ab$ on any tile (specular component included)
<b>Short-Term Repeatability</b>	.05 $\Delta E^*ab$ on white ceramic
<b>Measuring Time</b>	Approx. 2 seconds
<b>Transform Support</b>	Embedded
<b>Lamp Life</b>	Approx. 500,000 measurements
<b>Power Supply</b>	AC Adapter Requirements 90 – 130VAC or 100 – 240VAC, 50 – 60Hz, 15W max
<b>Data Interface</b>	USB
<b>Operating Temperature Range</b>	50° to 104°F (10° to 40°C) 85% relative humidity maximum (non-condensing)
<b>Storage Temperature Range</b>	-4° to 122°F (-20° to 50°C)
<b>Weight</b>	11.5 lbs. (5.2 kg)
<b>Dimensions</b>	8.7”H (22.0 cm) x 7.5”W (19.0 cm) x 10.4”L (26.4 cm)
<b>Accessories Provided</b>	Calibration standards: Black trap, White & green standards, UV Calibration standard (Ci4200UV), Operations manual, AC adapter, USB cable

## X-Rite Ci4200/Ci4200UV Features

- Embedded NetProfiler enables users to monitor the performance of their population of instruments, optimizing measurement agreement
- Data compatibility with X-Rite sphere handhelds
- Available with calibrated UV to maintain accurate measurements between optically brightened samples
- Correlated 60° gloss value
- Embedded transform enabled
- LED membrane provides status and operation feedback with remote trigger
- Sample targeting / viewing via sample arm
- Simultaneous SCI/SCE measurement in 2 seconds
- Vertical and horizontal positioning

